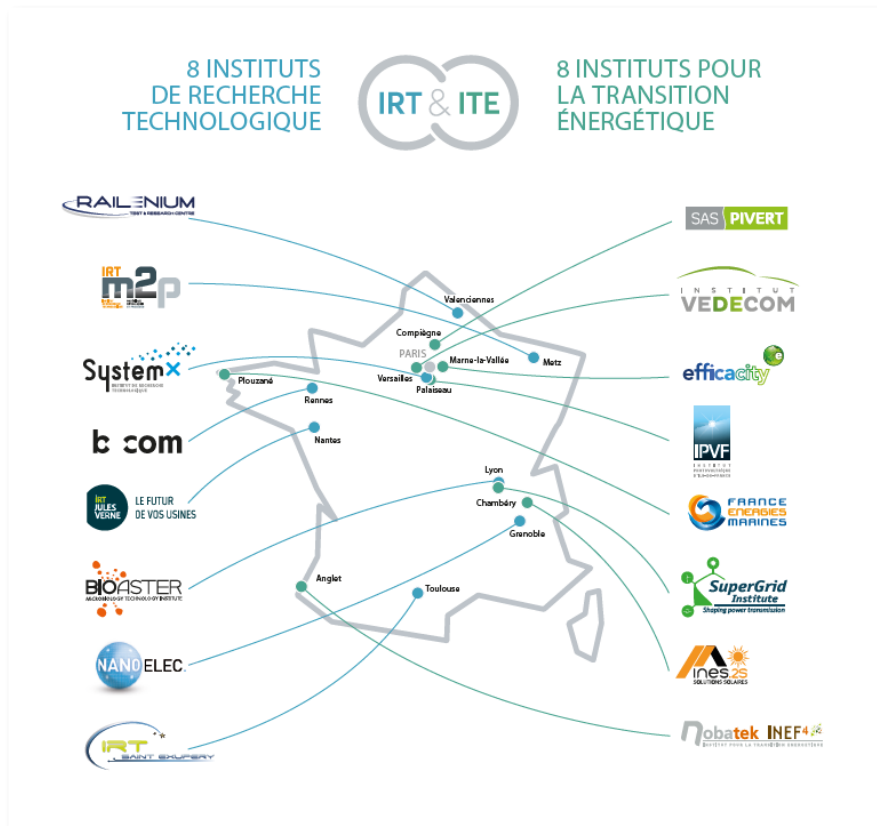


Eric Rouchouze

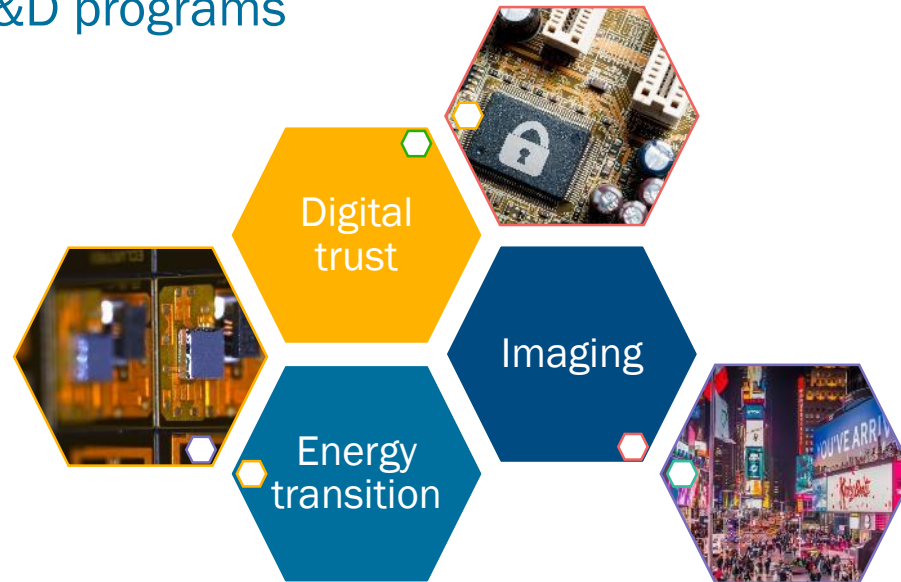
IRT Nanoelec and its CHARACTERIZATION program

November 24, 2020





- Address the main societal challenges by facilitating the link between technologies and applications
- Create value for the industrials partners to help them grow and address new markets, by fostering multi-partners R&D programs



Current Nanoelec partners

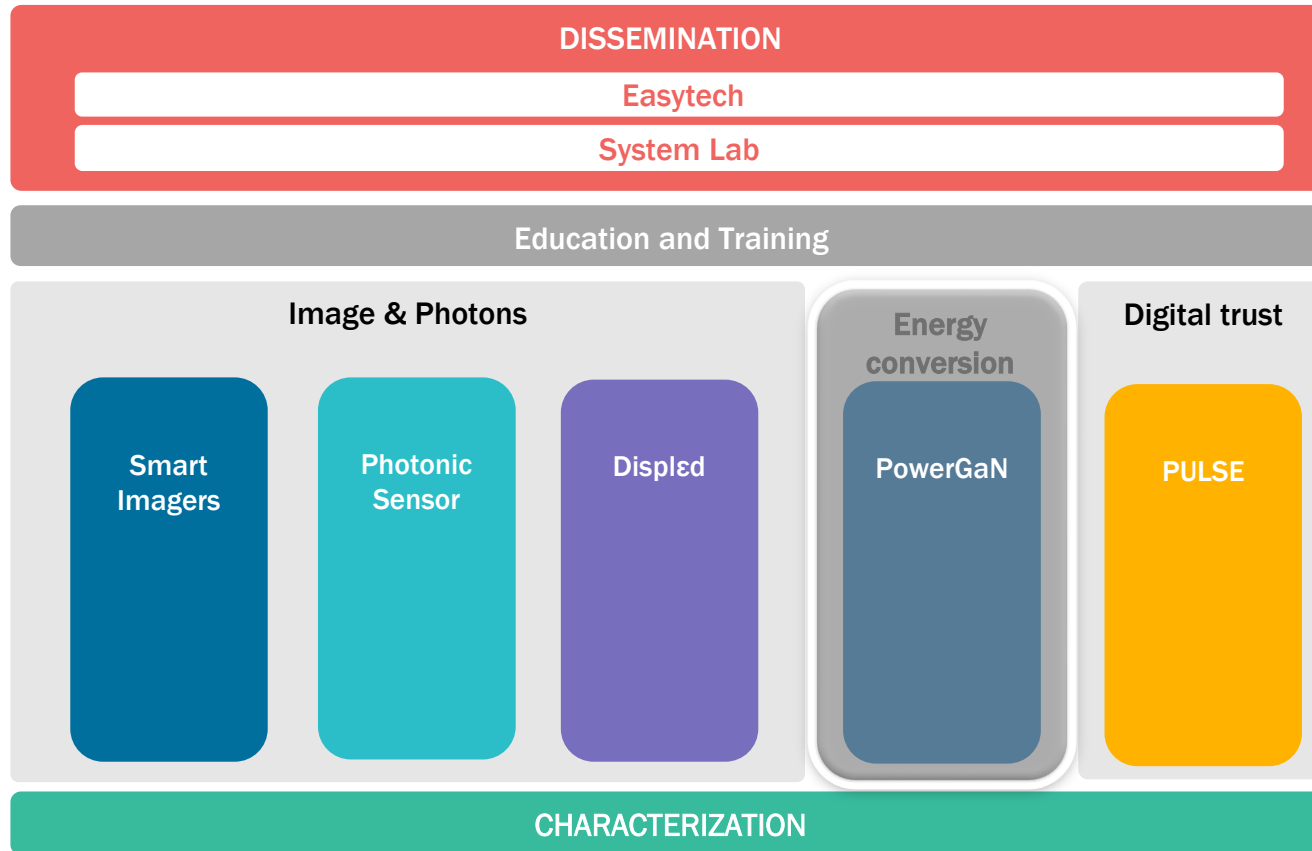


11 industrial partners

8 academics

1 pôle de compétitivité

1 association



- > **22** core partners
- > **238** Associated partners since 2012, *85 of them being active in 2019*
- > **54M€** mean budget on the 2015-2018 period (*60,1 M€ in 2019*)
- > **219** Full time positions engaged on our programs on the 2015-2019 period (*269 in 2019*)
- > **4** new companies
- > **173** patents et **36** software filled (*2019: 35 patents, 16 software*)
- > **394** scientific publications & communications since 2015 (*122 in 2019*)

- Bringing together the local characterization ecosystem to address the industry needs



- Current industrial partners



- Partners under discussion



Objective 1

Further develop the **physical characterization** service offer on our facilities to better serve the new stakes of the nanoelectronic industry

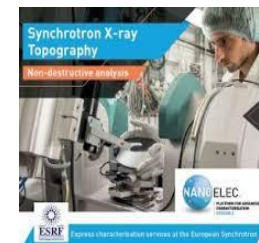
Objective 2

Set-up a brand new and unique state of the art **irradiation competence center**



> Markets

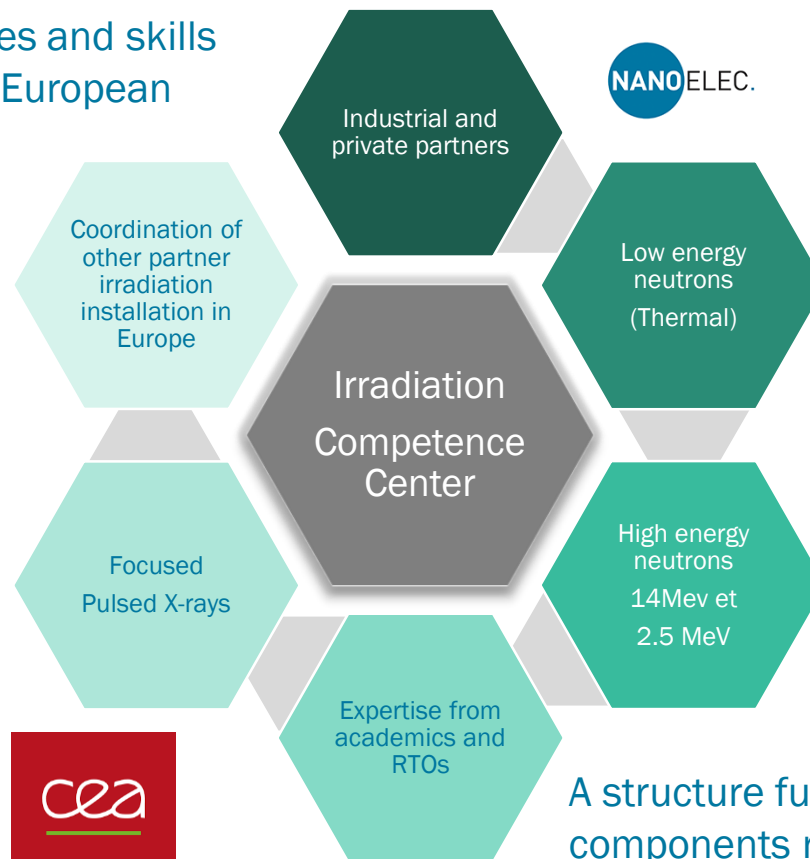
- Autonomous transportation
- Medical
- Spatial
- Data Centers
- IoT



Synchrotron X-ray solutions for high-throughput analysis of electronics components



Complementary facilities and skills
driven by the needs of European
industry



A structure fully dedicated to the electronic
components reliability to irradiation



STRESS AND STRAIN MEASUREMENT

Revealing stress and strain evolution during manufacture and use.



CRYSTAL QUALITY DETERMINATION

Applications in qualification, wafer characterisation and new process development.



INTERFACE CHARACTERISATION

Probing buried interfaces to evaluate manufacturing processes, analyse failure and delamination.



PROCESS MONITORING

In-situ process characterisation and optimisation of processing conditions.



HIGH RESOLUTION IMAGING

Imaging electronic components in 2D/3D down to nanometre resolutions for failure analysis.



IRRADIATION STUDIES

Investigating reliability and SEE sensitivity of electronic components and systems.

➤ Not only addressing microelectronics industry needs :

- Material science
- Welding
- Process control
- Other domains

A banner for the Workshop G-RAD. The background is a close-up of a blue and gold microchip with a network of white dots and lines overlaid. The text 'WORKSHOP G-RAD' is in large, bold, black letters on the left. Below it, 'GRENOBLE RADIATION TESTING OF SEMICONDUCTOR DEVICES AND SYSTEMS' is written in smaller black letters. On the right, 'NANO ELEC.' is written in white inside a white circle. At the bottom, an orange banner contains the text '09-10 DECEMBER 2020 · EPN CAMPUS, GRENOBLE' in white, italicized letters.

**WORKSHOP
G-RAD**

GRENOBLE RADIATION TESTING OF SEMICONDUCTOR DEVICES AND SYSTEMS

NANO ELEC.

09-10 DECEMBER 2020 · EPN CAMPUS, GRENOBLE

Thank you for your attention



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